

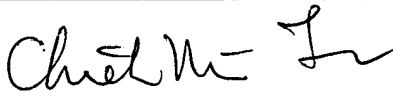



<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/879,434	YOO ET AL.	
	Examiner	Art Unit	
	Jason M. Perilla	2634	

ISSUE CLASSIFICATION											
ORIGINAL					CROSS REFERENCE(S)						
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
375		355			375	371	354				
INTERNATIONAL CLASSIFICATION											
H	0	4	L	7/00							
H	0	3	D	3/24							
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				/							
 Jason M. Perilla (Assistant Examiner) (Date) 6/7/05					 Chieh M. Fan (Primary Examiner) (Date) 6/8/05					Total Claims Allowed: 19	
 Lashawn Marks (Legal Instruments Examiner) (Date) 6/14/05										O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
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